Notice of References Cited

Application/Control No.	Applicant(s)/Pater	nt Under
10/693,546	Reexamination CHASE, JOHN F	₹.
Examiner	Art Unit	
SUZANNE LO	2128	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-7,085,702	08-2006	Hwang et al.	703/15
*	В	US-2004/0210798	10-2004	Higashi, Shinsaku	714/027
*	С	US-5,805,795	09-1998	Whitten, Thomas G.	714/38
*	D	US-6,907,550	06-2005	Webster et al.	714/47
*	Е	US-6,378,088	04-2002	Mongan, John Thomas	714/39
*	F	US-6,189,116	02-2001	Mongan et al.	714/38
*	G	US-6,678,645	01-2004	Rajsuman et al.	703/20
*	Н	US-6,334,207	12-2001	Joly et al.	716/17
		US-		-	
	J	US-			
	к	US-			
	٦	US-			
	м	US-			

FOREIGN PATENT DOCUMENTS

			,	FOREIGN PATENT DOC	UMENIS	
*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R					
	s					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
*	U	Bening et al. "Optimizing Multiple EDA Tools within the ASIC Design Flow", 2001, IEEE, IEEE Design & Test of Computers, pages 46-55
	v	
	w	
	×	

A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.